Analysis/determination of the crystal/molecular structure of a solid with the help of X-rays or neutrons means (because of the 3D periodicity of crystals): Determination of

- the geometry (lattice constants a, b, c,  $\alpha$ ,  $\beta$ ,  $\gamma$ )
- the symmetry (space group)
- the content (typ, site x<sub>j</sub>, y<sub>j</sub>, z<sub>j</sub> and thermal parameters B<sub>j</sub> of the atoms j)

of the unit cell of a crystalline compound and their analysis/interpretation with respect to chemical or physical problems or questions.

is based on diffraction of electromagnetic radiation or neutrons of suitable energies/wavelengths/velocities and one needs:

- a crystalline sample (powder or single crystal, V~0.01mm<sup>3</sup>)
- an adequate electromagnetic radiation ( $\lambda \sim 10^{-10}$  m)
- some knowledge of properties and diffraction of radiation
- some knowledge of structure and symmetry of crystals
- a diffractometer (with point and/or area detector)
- a powerful computer with the required programs for solution, refinement, analysis and visualization of the crystal structure
- some chemical feeling for interpretation of the results

If a substance is irradiated by electromagn. Radiation or neutrons of suitable wavelength, a small part of the primary radiation (~  $10^{-6}$ ) is scattered by the electrons or nuclei of the atoms /ions/molecules of the sample elastically ( $\Delta E = 0$ ) and coherently ( $\Delta \phi = \text{konstant}$ ) in all directions. The resulting scattering/diffraction pattern **R** is the Fourier transform of the elektron/scattering distribution function  $\rho$  of the sample and vice versa.



The shape of the resulting scattering/diffraction pattern depends on the degree of order of the sample.



B. X-ray scattering diagram of a crystalline sample



crystal powder orientation statistical,  $\lambda$  fixed  $\Rightarrow$  cones of interference



Debye-Scherrer diagram

single crystal orientation or  $\lambda$  variable  $\Rightarrow$  dots of interference (reflections)



#### precession diagram

Why that?

## Diffraction of X-rays or neutrons at a crystalline sample (single crystal or crystal powder)

X-rays scattered from a crystalline sample are <u>not totally extinct</u> only for those directions, where the <u>scattered rays are \_in phase</u><sup>\*</sup>. R(S) und  $I(\theta)$  therefore are periodic functions of \_Bragg reflections<sup>\*</sup>.



Bragg equation:  $n \cdot \lambda = 2d \cdot \sin \theta$  or  $\lambda = 2d_{(hkl)} \cdot \sin \theta_{(hkl)}$ 

# Basic equation of X-ray analysis: Bragg equation

Lattice planes: Why are they important?



Question: How are directions and planes in a regular lattice defined ?

Bragg equation:  $n\lambda = 2d \sin\theta$  $\lambda = 2d_{(hkl)} \sin\theta_{(hkl)}$ 





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### Lattice plane series: Miller indices hkl, d values



#### (X-ray) diffraction of a crystalline sample (single crystal or crystal powder) detector (film, imaging plate) $I(\theta)$ $\lambda = 2d_{hkl} \cdot \sin\theta_{hkl}$ (Bragg) $\vec{s}_0$ : WVIB scattered beam $\vec{s}$ : WVSB; $|\vec{s}| = |s_0| = 1/\lambda$ (or 1) $\vec{S} = \vec{s} - \vec{s}_0$ S: Scattering Vector $\vec{S}_0$ $\vec{S} = \vec{H} (Bragg)$ S<sub>0</sub> incident beam stop x-ray sample beam source $n \cdot \lambda = 2d \sin \theta$ $S = 2sin\theta_{hkl}/\lambda = 1/d_{hkl} = H$

Fourier transform of the electron density distribution

sample  

$$\rho(\vec{r}) = \frac{\int_{V} \rho(\vec{r}) \exp(2\pi i \vec{r} \cdot \vec{S}) dV}{\rho(\vec{r}) = \frac{1}{V} \int_{V^*} R(\vec{S}) \exp(-2\pi i \vec{r} \cdot \vec{S}) dV^*}$$

$$diffr. pattern \qquad R \neq 0 \\ only if \qquad \vec{S} = \vec{H}$$



: scattering vector  $\equiv$  vector in Fourier (momentum) space

Analysis/determination of the crystal/molecular structure of a crystalline solid with the help of X-rays or neutrons therefore means:

Determination of

- the geometry (lattice constants a, b, c,  $\alpha$ ,  $\beta$ ,  $\gamma$ )
- the symmetry (space group)
- the content (type, site x<sub>j</sub>, y<sub>j</sub>, z<sub>j</sub> and thermal parameters B<sub>j</sub> of the atoms j)

of the unit cell of that crystalline compound from the scattering/diffraction pattern R(S) or  $I(\theta)$  or I(hkl)How does that work?

- The geometry (lattice constants a, b, c,  $\alpha$ ,  $\beta$ ,  $\gamma$ ) of the unit cell/ compond one can get from the geometry of the diffraction pattern, i.e. from the site of the reflections (diffraction angles  $\theta$ for a powder; "Euler angles"  $\theta$ ,  $\omega$ ,  $\varphi$ ,  $\chi$  for a single crystal)
- The symmetry (space group) one can get from the symmetry of the reflections and the systematically extinct reflections,
- The content of the unit cell (typ, site  $x_j$ ,  $y_j$ ,  $z_j$  and thermal parameters  $B_j$  of the atoms j) one can get from the intensities I(hkl) of the reflections and the respective phases  $\alpha$ (hkl).

 $|Fo(hkl)| \approx (I(hkl))^{1/2} \quad Fc(hkl) = \Sigma f_j \cdot exp(2\pi i(hx_j + ky_j + lz_j))$  $\delta(xyz) = (1/V) \cdot \Sigma |Fo(hkl)| \cdot exp(i\alpha(hkl) \cdot exp(-2\pi i(hx + ky + lz)))$ 

The structure factor is named Fo(hkl), if observed, i.e. derived from measured I(hkl) and Fc(hkl) if calculated from  $f_j$ ,  $x_j$ ,  $y_j$ ,  $z_j$ . Note that (hkl) represent lattice planes and hkl reflections.

- $\rightarrow$  The intensitis  $I_{hkl}$  of the reflections (i.e. of the reciprocal lattice points) thus reflect the atomic arrangement of the real crystal structure.
- $\rightarrow$  Each intensity I(hkl) or I<sub>hkl</sub> is proportional to the the square of a quantity called structure factor F(hkl) or F<sub>hkl</sub> (Fo for observed, Fc for calculated).
- $\rightarrow$  The structure factor F(hkl) is a complex number in general but becomes real in case of crystal structures with a centre of symmetry:

$$F(hkl) = F_{hkl} = \sum_{j} f_{j} \cos 2\pi (hx_{j} + ky_{j} + lz_{j})$$

 $\rightarrow$  In case of centrosymmetric crystal structures, the phases are 0 or  $\pi$ , i.e. "only" the signs instead of the phases of the structure factors have to be determined.

The problem is that the phases/signs are lost upon measurement of the intensities of the reflections (phase problem of crystal structure analysis/determination)



Structure determination only indirectly possible!

![](_page_13_Figure_1.jpeg)

1. Fixing und centering of a crystal on a diffractometer and determination of the orientaion matrix M and the lattice constants a, b, c,  $\alpha$ ,  $\beta$ ,  $\gamma$  of the crystal from the Eulerian angles of the reflections ( $\theta$ ,  $\omega$ ,  $\varphi$ ,  $\chi$ ) and of the cell content number Z (aus cell volume, density and formula),

![](_page_14_Figure_2.jpeg)

Principle of a four-circle diffraktometer for single crystal stucture determination by use of X-ray or neutron diffraction

### CAD4 (Kappa-Axis-Diffraktometer)

![](_page_15_Picture_1.jpeg)

![](_page_15_Picture_2.jpeg)

![](_page_16_Picture_0.jpeg)

#### X-ray analysis with single crystals: Reciprocal lattice (calculated from an IPDS measurement)

![](_page_17_Picture_1.jpeg)

- 2. Determination of the space group (from symmetry and systematic extinctions of the reflections)
- 3. Measuring of the intensities I(hkl) of the reflections (asymmetric part of the reciprocal lattice up to  $0.5 \le \sin\theta/\lambda \le 1.1$  is sufficient)
- 4. Calculation of the structure amplitudes  $|Fo_{hkl}|$  from the  $I_{hkl}$  incl. absorption, extinktion, LP correction  $\rightarrow$  data reduction
- 5. Determination of the scale factor K and of the mean temperature parameter B for the compound under investigation from the mean  $|Fo_{hkl}|$  values for different small  $\theta$  ranges  $\theta_m$  according to  $\ln(|Fo|^2/\Sigma f_i^2) = \ln(1/K) - 2B(\sin^2\theta_m)/\lambda^2 \rightarrow data skaling$

- 6a. Determin. of the phases  $\alpha_{hkl}$  of the structure amplitudes  $|Fo_{hkl}| \rightarrow$  phase determination (phase problem of structure analysis)
  - trial and error (model, than proff of the scattering pattern)
  - calculation of the Patterson function

 $P_{(uvw)} = (1/V) \cdot \Sigma |F_{hkl}|^2 \cos 2\pi (hu + kv + lw)$ 

from the structure amplitudes resulting in distance vectors between all atoms of the unit cell

![](_page_19_Figure_6.jpeg)

Points to the distribution and position of ,,heavy atoms" in the unit cell  $\rightarrow$  heavy atom method

6b. Determin. of the phases  $\alpha_{hkl}$  of the structure amplitudes  $|Fo_{hkl}|$ 

• direct methodes for phase determination phases  $\alpha_{hkl}$  and intensity distribution are not indipendant from each other  $\rightarrow$  allowes determination of the phases  $\alpha_{hk}l$ 

e.g.  $F(hkl) \sim \Sigma\Sigma\Sigma F(h'k'l') \cdot F(h-h',k-k',l-l')$  (Sayre, 1952)

oder S(F<sub>hkl</sub>) ~ S(F<sub>h'k'l'</sub>)·S(F<sub>h-h',k-k',l-l'</sub>) (S = sign of F)

direct methodes today are the most important methodes for the solving the phase problem of structur analysis/determination

• anomalous dispersion methodes use the phase and intensity differences in the scattering near and far from absorption edges (measuring with X-rays of different wave lengths necessary)

7. Calculation of the electron density distribution function

 $\delta(xyz) = (1/V) \cdot \Sigma |Fo_{hkl}| \cdot exp(i\alpha_{hkl} \cdot exp(-2\pi i(hx+ky+lz))) of the$ 

unit cell from the structure amplitudes  $|Fo_{hkl}|$  and the phases  $\alpha_{hkl}$  of the reflections hkl (using B and K)  $\rightarrow$  Fourier synthesis

![](_page_21_Figure_4.jpeg)

Platin-Phthalocyanin,  $PtC_{32}H_{16}N_8$ : Elektronendichteprojektion  $\rho(xz)$ .

and determination of the elements and the atom sites  $x_j$ ,  $y_j$ ,  $z_{j^{22}}$ 

 Calculation of the structure factors Fc<sub>hkl</sub> (c: calculated) by use of these atomic sites/coordinates x<sub>j</sub>, y<sub>j</sub>, z<sub>j</sub> and the atomic form factors (atomic scattering factors) f<sub>i</sub> according to

 $Fc_{hkl} = \Sigma f_j \cdot exp(2\pi i(hx_j + ky_j + lz_j))$ 

9. Refinement of the scale factor K, the temperature parameter B (or of the individuel B<sub>j</sub> of the atoms j of the unit cell) and of the atomic coordinates x<sub>j</sub>,y<sub>j</sub>,z<sub>j</sub> by use of the least squares method, LSQ via minimising the function

 $(\Delta F)^2 = (|F_0| - |F_c|)^2$  for all measured reflections hkl

agreement factor:  $R = \Sigma |(|F_o| - |F_c|)| / \Sigma |F_o|$ 

10. Calculation of the bond lengths and angles etc. and graphical visualisation of the structure (structure plot)

![](_page_23_Figure_1.jpeg)

![](_page_23_Figure_2.jpeg)

![](_page_23_Figure_3.jpeg)

#### Crystallographic and structure refinement data of Cs<sub>2</sub>Co(HSeO<sub>3</sub>)<sub>4</sub>·2H<sub>2</sub>O

Name	Figure	Name	Figure
Formula	Cs <sub>2</sub> Co(HSeO <sub>3</sub> ) <sub>4</sub> ·2H <sub>2</sub> O	Diffractometer	IPDS (Stoe)
Temperature	293(2) K	Range for data collection	3.1° ≤Θ≤ 30.4 °
Formula weight	872.60 g/mol	hkl ranges	$-10 \le h \le 10$
Crystal system	Monoclinic		$-17 \le k \le 18$
Space group	$P 2_1/c$		$-10 \le l \le 9$
Unit cell dimensions	a = 757.70(20)  pm	Absorption coefficient	$\mu = 15.067 \text{ mm}^{-1}$
	<i>b</i> = 1438.80(30) pm	No. of measured reflections	9177
	c = 729.40(10)  pm	No. of unique reflections	2190
	$\beta = 100.660(30)^{\circ}$	No. of reflections $(I_0 \ge 2\sigma(I))$	1925
Volume	$781.45(45) \times 10^6 \text{ pm}^3$	Extinction coefficient	$\varepsilon = 0.0064$
Formula units per unit cell	Z = 2	$\Delta  ho_{min}$ / $\Delta  ho_{max}$ / e/pm <sup>3</sup> × 10 <sup>-6</sup>	-2.128 / 1.424
Density (calculated)	3.71 g/cm <sup>3</sup>	$R_1 / wR_2 (I_0 \ge 2\sigma (I))$	0.034 / 0.081
Structure solution	SHELXS – 97	$R_1 / wR_2$ (all data)	0.039 / 0.083
Structure refinement	SHELXL – 97	Goodness-of-fit on $F^2$	1.045
Refinement method	Full matrix LSQ on $F^2$		

#### Positional and isotropic atomic displacement parameters of Cs<sub>2</sub>Co(HSeO<sub>3</sub>)<sub>4</sub>·2H2O

Atom	WP	X	У	Z	U <sub>eq</sub> /pm <sup>2</sup>
Cs	4e	0.50028(3)	0.84864(2)	0.09093(4)	0.02950(11)
Со	2a	0.0000	1.0000	0.0000	0.01615(16)
Se1	4e	0.74422(5)	0.57877(3)	0.12509(5)	0.01947(12)
011	4e	0.7585(4)	0.5043(3)	0.3029(4)	0.0278(7)
012	4e	0.6986(4)	0.5119(3)	-0.0656(4)	0.0291(7)
013	4e	0.5291(4)	0.6280(3)	0.1211(5)	0.0346(8)
H11	4e	0.460(9)	0.583(5)	0.085(9)	0.041
Se2	4e	0.04243(5)	0.67039(3)	-0.18486(5)	0.01892(12)
021	4e	-0.0624(4)	0.6300(2)	-0.3942(4)	0.0229(6)
022	4e	0.1834(4)	0.7494(3)	-0.2357(5)	0.0317(7)
023	4e	-0.1440(4)	0.7389(2)	-0.1484(4)	0.0247(6)
H21	4e	-0.120(8)	0.772(5)	-0.062(9)	0.038
OW	4e	-0.1395(5)	1.0685(3)	0.1848(5)	0.0270(7)
HW1	<i>4e</i>	-0.147(8)	1.131(5)	0.032	0.032
HW2	4e	-0.159(9)	1.045(5)	0.247(9)	0.032

#### Anisotropic thermal displacement parameters $Uij \times 104 / pm2$ of $Cs_2Co(HSeO_3)_4 \cdot 2H_2O$

Atom	U <sub>11</sub>	U <sub>22</sub>	U <sub>33</sub>	U <sub>12</sub>	U <sub>13</sub>	U <sub>23</sub>
Cs	0.0205(2)	0.0371(2)	0.0304(2)	0.00328(9)	0.0033(1)	-0.00052(1)
Со	0.0149(3)	0.0211(4)	0.0130(3)	0.0006(2)	0.0041(2)	0.0006(2)
Se1	0.0159(2)	0.0251(3)	0.01751(2)	-0.00089(1)	0.00345(1)	0.00097(1)
011	0.0207(1)	0.043(2)	0.0181(1)	-0.0068(1)	-0.0013(1)	0.0085(1)
012	0.0264(2)	0.043(2)	0.0198(1)	-0.0009(1)	0.0089(1)	-0.0094(1)
013	0.0219(1)	0.034(2)	0.048(2)	0.0053(1)	0.0080(1)	-0.009(2)
Se2	0.0179(2)	0.0232(2)	0.0160(2)	0.00109(1)	0.00393(1)	-0.0001(1)
O21	0.0283(1)	0.024(2)	0.0161(1)	0.0008(1)	0.0036(1)	-0.0042(1)
O22	0.0225(1)	0.032(2)	0.044(2)	-0.0058(1)	0.0147(1)	-0.0055(1)
023	0.0206(1)	0.030(2)	0.0240(1)	0.0018(1)	0.0055(1)	-0.0076(1)
OW	0.0336(2)	0.028(2)	0.0260(2)	0.0009(1)	0.0210(1)	-0.0006(1)

The anisotropic displacement factor is defined as: exp  $\{-2p2[U11(ha^*)2 + ... + 2U12hka^*b^*]\}$ 

#### Some selected bond lengths (/pm) and angles(/°) of $Cs_2Co(HSeO_3)_4 \cdot 2H_2O$

CsO <sub>9</sub> polyhedron			
Cs-O11	316.6(3)	O22-Cs-OW	78.76(8)
Cs-O13	318.7(4)	O22-Cs-O12	103.40(9)
Cs-O22	323.7(3)	O23-Cs-O11	94.80(7)
Cs-O23	325.1(3)	O13-Cs-O11	42.81(8)
Cs-OW	330.2(4)	O11-Cs-O23	127.96(8)
Cs-O21	331.0(3)	O13-Cs-O22	65.50(9)
Cs-O12	334.2(4)	O22-Cs-O22	66.96(5)
Cs-O22	337.1(4)	O11-Cs-OW	54.05(8)
Cs-O13	349.0(4)	O23-Cs-O22	130.85(9)
CoO <sub>6</sub> octahedron			
Co-OW	210.5(3)	OW-Co-OW	180
Co-O11	210.8(3)	OW-Co-O21	90.45(13)
Co-O21	211.0(3)	OW-Co-O11	89.55(13)

SeO <sub>3</sub> <sup>2-</sup> anions					
Se1-O11	167.1(3)		O12- Se1-O11	104.49(18)	
Se1-O12	167.4(3)		O12- Se1-O13	101.34(18)	
Se1-O13	177.2(3)		O11- Se1-O13	99.66(17)	
Se2-O21	168.9(3)		O22- Se2-O21	104.46(17)	
Se2-O22	164.8(3)		O22- Se2-O23	102.51(17)	
Se2-O23	178.3(3)		O21- Se2-O23	94.14(15)	
Hydrogen bonds		d(O-H)	d(O…H)	d(O…O)	<0H0>
O13-H11.	·O12	85(7)	180(7)	263.3(5)	166(6)
O23-H21O21		78(6)	187(7)	263.7 (4)	168(7)
OW-HW1···O22		91(7)	177(7)	267.7 (5)	174(6)
OW-HW2 <sup>…</sup> O12		61(6)	206(6)	264.3 (4)	161(8)

#### Symmetry codes:

- 1.-x, -y+2, -z2.-x+1, -y+2, -z3.-x+1, y-1/2, -z+1/24.x-1, -y+3/2, z-1/25.x, -y+3/2, z-1/26.x, -y+3/2, z+1/27.-x, y-1/2, -z-1/28.-x+1, y+1/2, -z+1/29.x+1, -y+3/2, z+1/210.-x, y+1/2, -z-1/211.-x+1, -y+1, -z12.x-1, -y+3/2, z+1/2

![](_page_28_Figure_1.jpeg)

![](_page_28_Figure_2.jpeg)

Connectivity of the coordination polyhedra of Cs<sub>2</sub>Co(HSeO<sub>3</sub>)<sub>4</sub>·2H<sub>2</sub>O

![](_page_29_Figure_1.jpeg)

Hydrogen bonds of Cs<sub>2</sub>Co(HSeO<sub>3</sub>)<sub>4</sub>·2H<sub>2</sub>O

![](_page_29_Figure_3.jpeg)

Anions and hydrogen bonds of  $Cs_2Co(HSeO_3)_4$ ·2H<sub>2</sub>O

![](_page_29_Figure_5.jpeg)

Crystal structure of Cs<sub>2</sub>Co(HSeO<sub>3</sub>)<sub>4</sub>·2H<sub>2</sub>O

### Course of a crystal structure analysis

![](_page_30_Figure_1.jpeg)

## Literature

•*Röntgenfeinstrukturanalyse* von **H. Krischner**, Vieweg (Allgemeine Einführung, Schwerpunkt Pulvermethoden) oder alternativ

•*Röntgen-Pulverdiffraktometrie* von **Rudolf Allmann**, Clausthaler Tektonische Hefte 29, Sven von Loga, 1994

•Kristallstrukturbestimmung von W. Massa, Teubner, Stuttgart, 1984

•Untersuchungsmethoden in der Chemie von H. Naumer und W. Heller, Wiley-VCH

(Einführung in die moderne Analytik und Strukturbestimmungsmethoden)

•*X-Ray Structure Determination* von **G. H. Stout, L.H. Jensen,** MacMillan, London

(Einführung in die Kristallstrukturanalyse für Fortgeschrittene)